

HANDBOOK OF ELECTRONIC MATERIALS
Volume 5

HANDBOOK OF ELECTRONIC MATERIALS

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ELECTRONIC PROPERTIES INFORMATION CENTER
Hughes Aircraft Company
Culver City, California

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Volume 5

Group IV Semiconducting Materials

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Hughes Aircraft Company, Culver City, California*

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FOREWORD

This report was prepared by Hughes Aircraft Company, Culver City, California under Contract Number F33615-70-C-1348. The work was administered under the direction of the Air Force Materials Laboratory, Air Force Systems Command, Wright-Patterson Air Force Base, Ohio, with Mr. B. Emrich, Project Engineer.

The Electronic Properties Information Center (EPIC) is a designated Information Analysis Center of the Department of Defense, authorized to provide information to the entire DoD community. The purpose of the Center is to provide a highly competent source of information and data on the electronic, optical and magnetic properties of materials of value to the Department of Defense. Its major function is to evaluate, compile and publish the experimental data from the world's unclassified literature concerned with the properties of materials. All materials relevant to the field of electronics are within the scope of EPIC: insulators, semiconductors, metals, superconductors, ferrites, ferroelectrics, ferromagnetics, electroluminescents, thermionic emitters and optical materials. The Center's scope includes information on over 100 basic properties of materials; information generally regarded as being in the area of devices and/or circuitry is excluded.

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